

BS EN 62047-12:2011



BSI Standards Publication

Semiconductor devices — Micro-electromechanical devices

Part 12: Bending fatigue testing method
of thin film materials using resonant vibration
of MEMS structures

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National foreword

This British Standard is the UK implementation of EN 62047-12:2011. It is identical to IEC 62047-12:2011.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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Amendments issued since publication

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